

Appl. No.
Amtd. Dated July 28, 2005
Reply to Office Action of

REMARKS

Applicant thanks the Examiner for acknowledging receipt of foreign priority document, Japanese Application No. JP2000-251241, that had been submitted pursuant to 35 U.S.C. § 119 and/or PCT Rule 17.2(a) in parent Application No. 09/934154.

Applicant respectfully requests reconsideration of Examiner's rejection of claim 6 under 35 U.S.C. §102(b). Examiner has rejected this claim in view of the cited prior art reference of *Sano et al.* (U.S. Patent No. 5,796,154). The *Sano* reference is directed to a solid-state imaging device with dual lens structure, wherein a second microlens located in the lower part of the device directs the light more vertically such that a convergent rate of the oblique incident light can be prevented from decreasing. (See the Abstract of the invention). However, *Sano* teaches that the lower microlens is comprised of a polypara-vinyl-phenol-based resin (See Col. 7, lines 47 – 51). Such a composition fails to teach or suggest Applicant's currently claimed invention, which requires the use of a lower convex lens comprised of a P-SiN or P-SiO₂ compound, which Applicants have discovered has a sufficiently high light transmittance at the required thicknesses of the current invention. (See page 20 of Applicant's invention).

The Examiner's remaining references cited but not relied upon, considered either alone or in combination, also fail to teach Applicant's currently claimed invention. In light of the foregoing, Applicant respectfully submits that all claims now stand in condition for allowance.

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